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MNLM6161-X REV 2B1

 Original Creation Date: 08/03/95
 Last Update Date: 09/04/02
 Last Major Revision Date: 10/28/98

HIGH SPEED OPERATIONAL AMPLIFIER
General Description

The LM6161 high-speed amplifier exhibits an excellent speed-power product in delivering 300 V/uS and 50 MHz unity gain stability with only 5 mA of supply current. Further, power savings and application convenience are possible by taking advantage of the wide dynamic range in operating supply voltage which extends all the way down to +5V.

This amplifier is built with National's VIP[™] (Vertically Integrated PNP) process which provides fast PNP transistors that are true complements to the already fast NPN devices. This advanced junction-isolated process delivers high speed performance without the need for complex and expensive dielectric isolation.

Industry Part Number

LM6161

Prime Die

LM6161B

NS Part Numbers

 LM6161E/883
 LM6161J-QMLV
 LM6161J/883
 LM6161W/883
 LM6161WG-QMLV
 LM6161WG/883

Controlling Document

SEE FEATURES SECTION

Processing

MIL-STD-883, Method 5004

Quality Conformance Inspection

MIL-STD-883, Method 5005

| Subgrp | Description | Temp (°C) |
|--------|---------------------|------------|
| 1 | Static tests at | +25 |
| 2 | Static tests at | +125 |
| 3 | Static tests at | -55 |
| 4 | Dynamic tests at | +25 |
| 5 | Dynamic tests at | +125 |
| 6 | Dynamic tests at | -55 |
| 7 | Functional tests at | +25 |
| 8A | Functional tests at | +125 |
| 8B | Functional tests at | -55 |
| 9 | Switching tests at | +25 |
| 10 | Switching tests at | +125 |
| 11 | Switching tests at | -55 |

Features

- High slew rate 300V/uS
- High unity gain freq 50MHz
- Low supply current 5mA
- Fast settling 120nS to 0.1%
- Low differential gain <0.1%
- Low differential phase 0.1 degrees
- Wide supply range 4.75V to 32V
- Stable with unlimited capacitive load
- Well behaved; easy to apply

CONTROLLING DOCUMENT:

| | |
|---------------|-----------------|
| LM6161E/883 | 5962-89621012A |
| LM6161J-QMLV | 5962-8962101VPA |
| LM6161J/883 | 5962-8962101PA |
| LM6161W/883 | 5962-8962101HA |
| LM6161WG-QMLV | 5962-8962101VXA |
| LM6161WG/883 | 5962-8962101XA |

Applications

- Video amplifier
- High-frequency filter
- Wide-bandwidth signal conditioning
- Radar
- Sonar

(Absolute Maximum Ratings)

(Note 1)

| | |
|--|---|
| Supply Voltage (V+ - V-) | 36V |
| Differential Input Voltage Range (Note 4) | ±8V |
| Common-Mode Voltage Range (Note 6) | (V+ - 0.7V) to (V- - 7V) |
| Output Short Circuit to Gnd (Note 3) | Continuous |
| Power Dissipation (Note 2) | 400mW |
| Soldering Information (Soldering, 10 seconds) | 260 C |
| Storage Temperature Range | -65 C to +150 C |
| Maximum Junction Temperature | 150 C |
| Thermal Resistance | |
| ThetaJA | |
| LCC | (Still Air) 90 C/W (500LF/Min Air flow) 61 C/W |
| CERDIP | (Still Air) 113 C/W (500LF/Min Air flow) 51 C/W |
| CERPAK | (Still Air) 228 C/W (500LF/Min Air flow) 140 C/W |
| CERAMIC SOIC | (Still Air) 228 C/W (500LF/Min Air flow) 140 C/W |
| ThetaJC | |
| LCC | 20 C/W |
| CERDIP | 21 C/W |
| CERPAK | 21 C/W |
| CERAMIC SOIC | 21 C/W |
| ESD Tolerance (Note 4, 5) | ±500V |

- Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.
- Note 2: The maximum power dissipation must be derated at elevated temperatures and is dictated by Tjmax (maximum junction temperature), ThetaJA (package junction to ambient thermal resistance), and TA (ambient temperature). The maximum allowable power dissipation at any temperature is Pdmax = (Tjmax - TA)/ThetaJA or the number given in the Absolute Maximum Ratings, whichever is lower.
- Note 3: Continuous short-circuit operation at elevated ambient temperature can result in exceeding the maximum allowed junction temperature of 150 C.
- Note 4: In order to achieve optimum AC performance, the input stage was designed without protective clamps. Exceeding the maximum differential input voltage results in reverse breakdown of the base-emitter junction of one of the input transistors and probable degradation of the input parameters (especially Vio, Iio and Noise).
- Note 5: The average voltage that the weakest pin combinations (those involving Pin 2 or Pin 3) can withstand and still conform to the datasheet limits. The test circuit used consists of the human body model of 100pF in series with 1500 Ohms.
- Note 6: The voltage between V+ and either input pin must not exceed 36V.

Recommended Operating Conditions

(Note 1)

Temperature Range

$-55\text{ C} \leq \text{TA} \leq +125\text{ C}$

Supply Voltage Range

4.75V to 32V

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Electrical Characteristics

DC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: $V_{cc} = \pm 15V$, $V_{cm} = 0V$, $R_l \geq 100K$ Ohms, $R_s = 10K$ Ohms.

| SYMBOL | PARAMETER | CONDITIONS | NOTES | PIN-NAME | MIN | MAX | UNIT | SUB-GROUPS | |
|--------|------------------------------------|---------------------------------------|-------|----------|------|-------|------|------------|------|
| Vio | Input Offset Voltage | | | | -7 | 7 | mV | 1 | |
| | | | | | -10 | 10 | mV | 2, 3 | |
| Iib | Input Bias Current | | | | -3 | 3 | uA | 1 | |
| | | | | | -6 | 6 | uA | 2, 3 | |
| Iio | Input Offset Current | | | | -350 | 350 | nA | 1 | |
| | | | | | -800 | 800 | nA | 2, 3 | |
| +Vcmr | Positive Common-Mode Voltage Range | $V_{cc} = \pm 15V$ | | | 13.9 | | V | 1 | |
| | | | | | 13.8 | | V | 2, 3 | |
| | | $V_{cc} = +5V$ | | | 2 | 3.9 | | V | 1 |
| | | | | | 2 | 3.8 | | V | 2, 3 |
| -Vcmr | Negative Common-Mode Voltage Range | $V_{cc} = \pm 15V$ | | | | -12.9 | V | 1 | |
| | | | | | | -12.7 | V | 2, 3 | |
| | | $V_{cc} = +5V$ | | | 2 | | 2.0 | V | 1 |
| | | | | | 2 | | 2.2 | V | 2, 3 |
| CMRR | Common-Mode Rejection Ratio | $-12.9V \leq V_{cm} \leq 13.9V$ | | | 80 | | dB | 1 | |
| | | $-12.7V \leq V_{cm} \leq 13.8V$ | | | 74 | | dB | 2, 3 | |
| PSRR | Power Supply Rejection Ratio | $\pm 10V \leq V_{cc} \leq \pm 16V$ | | | 80 | | dB | 1 | |
| | | | | | 74 | | dB | 2, 3 | |
| Ios | Output Short Circuit Current | Source | | | | -30 | mA | 1 | |
| | | | | | | -20 | mA | 2, 3 | |
| | | Sink | | | 30 | | mA | 1 | |
| | | | | | 20 | | mA | 2, 3 | |
| Icc | Supply Current | | | | | 6.5 | mA | 1 | |
| | | | | | | 6.8 | mA | 2, 3 | |
| Avs | Large Signal Voltage Gain | $V_{out} = \pm 10V$, $R_l = 2K$ Ohms | 1 | | 550 | | V/V | 1 | |
| | | | 1 | | 300 | | V/V | 2, 3 | |
| +Vop | Positive Voltage Swing | $V_{cc} = \pm 15V$, $R_l = 2K$ Ohms | | | 13.5 | | V | 1 | |
| | | | | | 13.3 | | V | 2, 3 | |
| | | $V_{cc} = +5V$, $R_l = 2K$ Ohms | | | 3.5 | | V | 1 | |
| | | | | | 3.3 | | V | 2, 3 | |

Electrical Characteristics

DC PARAMETERS (Continued)

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: $V_{cc} = \pm 15V$, $V_{cm} = 0V$, $R_l \geq 100K$ Ohms, $R_s = 10K$ Ohms.

| SYMBOL | PARAMETER | CONDITIONS | NOTES | PIN-NAME | MIN | MAX | UNIT | SUB-GROUPS |
|--------|------------------------|--------------------------------------|-------|----------|-----|-------|------|------------|
| -Vop | Negative Voltage Swing | $V_{cc} = \pm 15V$, $R_l = 2K$ Ohms | | | | -13.0 | V | 1 |
| | | | | | | -12.7 | V | 2, 3 |
| | | $V_{cc} = +5V$, $R_l = 2K$ Ohms | | | | 1.7 | V | 1 |
| | | | | | | 2.0 | V | 2, 3 |

AC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)
AC: $V_{cc} = \pm 15V$, $V_{cm} = 0V$, $R_l \geq 100K$ Ohms, $R_s = 10K$ Ohms.

| | | | | | | | | |
|-----|------------------------|--|--|--|-----|-----|------|--------|
| Gbw | Gain Bandwidth Product | $f = 20Mhz$ | | | 40 | | Mhz | 4 |
| | | | | | 30 | | Mhz | 5, 6 |
| +Sr | Slew Rate | Output step = -4V to +4V, $A_v = +1$, $V_{in} = 8V$ step | | | 200 | | V/uS | 4 |
| | | | | | 180 | | V/uS | 5, 6 |
| -Sr | Slew Rate | Output step = +4V to -4V, $A_v = +1$, $V_{in} = 8V$ step | | | 200 | | V/uS | 4 |
| | | | | | 180 | | V/uS | 5, 6 |
| ts | Setting Time | 10V step to 0.1% , $A_v = 1$, $R_l = 2K$ Ohms | | | | 300 | nS | 9 |
| | | | | | | 325 | nS | 10, 11 |

DC PARAMETERS: DRIFT VALUES

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: $V_{cc} = \pm 15V$, $V_{cm} = 0V$, $R_l \geq 100K$ Ohms, $R_s = 10K$ Ohms. Delta Calculations Performed on QMLV Devices at Group B, Subgroup 5 ONLY.

| | | | | | | | | |
|------|-----------------------------|----------------------------------|--|--|------|------|----|---|
| Vio | Input Offset Voltage | | | | -0.7 | +0.7 | mV | 1 |
| Iib | Input Bias Current | | | | -0.5 | +0.5 | uA | 1 |
| Iio | Input Offset Current | | | | -35 | +35 | nA | 1 |
| CMRR | Common Mode Rejection Ratio | $-12.9V \leq +V_{cm} \leq 13.9V$ | | | -5 | +5 | dB | 1 |

Note 1: Voltage gain is the total output swing (20V) divided by the signal required to produce that swing.

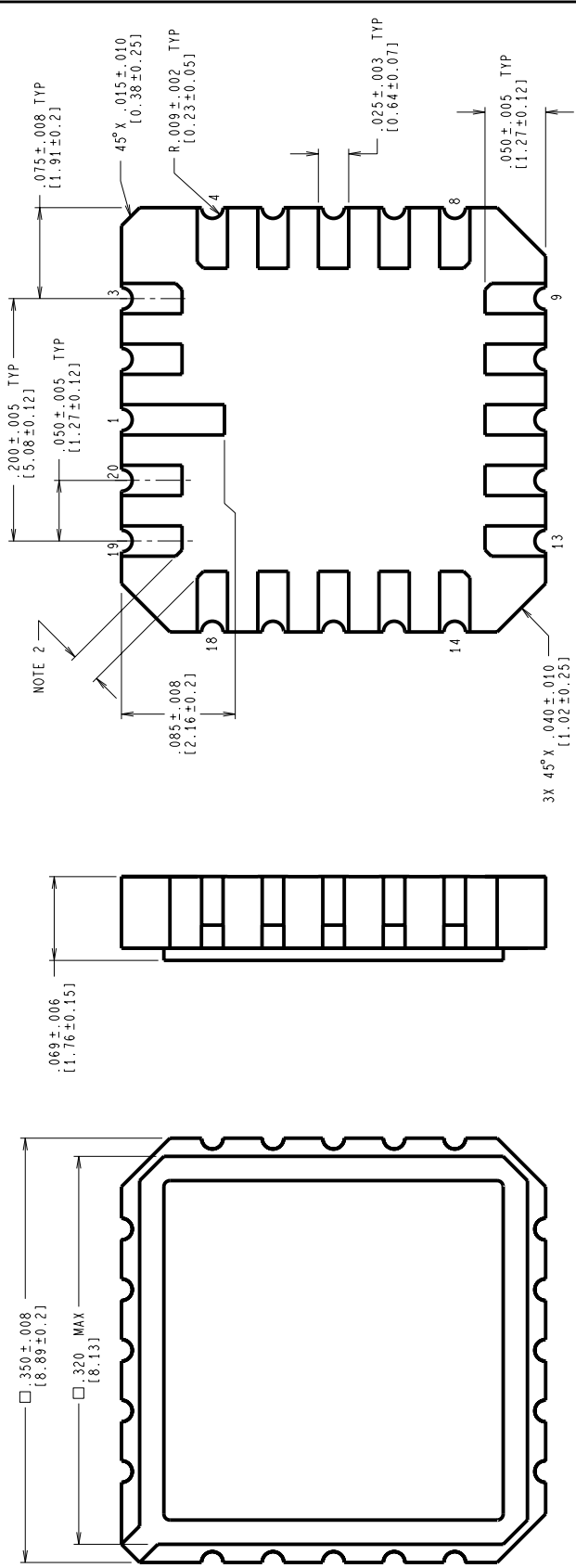
Note 2: For single supply operation, the following conditions apply: $V_+ = 5V$, $V_- = 0V$, $V_{cm} = 2.5V$, $V_{out} = 2.5V$. Vio adjust pins are each connected to V_- to realize maximum output swing. This connection will degrade Vio.

Graphics and Diagrams

| GRAPHICS# | DESCRIPTION |
|-----------|--|
| 05885HRA4 | CERDIP (J), 8 LEAD (B/I CKT) |
| 06190HRA3 | CERPACK (W, WG), 10LD (B/I CKT) |
| 06191HRA2 | LCC (E), TYPE C, 20 TERMINAL (B/I CKT) |
| E20ARE | LCC (E), TYPE C, 20 TERMINAL(P/P DWG) |
| J08ARL | CERDIP (J), 8 LEAD (P/P DWG) |
| P000167A | CERPACK (W), 10 LEAD (PINOUT) |
| P000168B | LCC (E), 20 LEAD, TYPE C (PINOUT) |
| P000169A | CERDIP (J), 8 LEAD (PINOUT) |
| P000259A | CERAMIC SOIC (WG), 10 LEAD (PINOUT) |
| W10ARG | CERPACK (W), 10 LEAD (P/P DWG) |
| WG10ARC | CERAMIC SOIC (WG), 10 LEAD (P/P DWG) |

See attached graphics following this page.

| REVISIONS | | | |
|-----------|-------------------|--------|---------------|
| LTR | DESCRIPTION | E.C.N. | DATE |
| E | REVISE AND REDRAW | 10005 | 02/10/94 DEG/ |



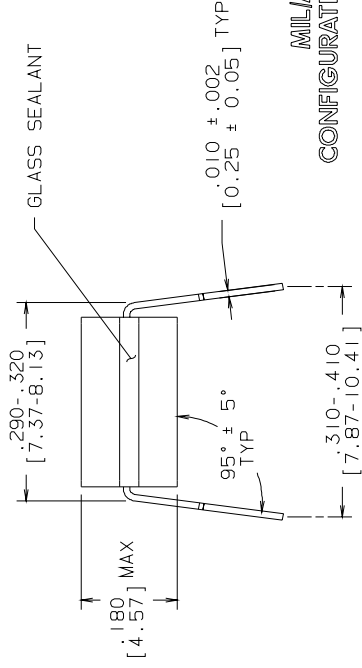
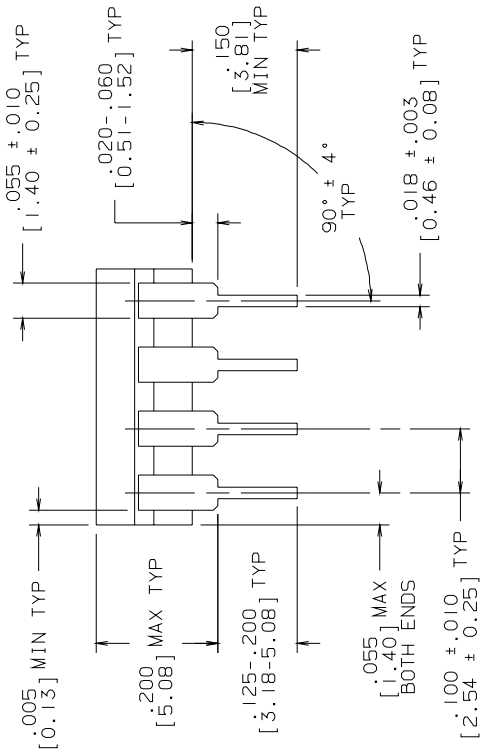
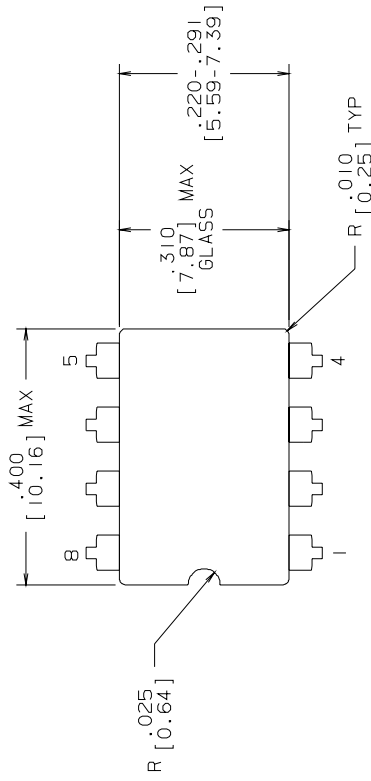
CONTROLLING DIMENSION IS INCH
VALUES IN [] ARE MILLIMETERS

- NOTES: UNLESS OTHERWISE SPECIFIED.
- LEAD FINISH TO BE ONE OF THE FOLLOWING:
 - 50 MICRONS/12.7 MICROMETERS MINIMUM GOLD PLATING OVER 50-350 MICRONS/1.27-8.89 MICROMETERS NICKEL.
 - SOLDER DIP.
 - SOLDER THICKNESS PER LATEST REVISION OF MIL-STD-1835.
 - CORNER PADS MAY HAVE A $45^\circ \times .020 \text{ IN}/0.51 \text{ mm}$ MAXIMUM CHAMFER TO ACCOMPLISH THE $.015 \text{ IN}/0.38 \text{ mm}$ DIMENSION.
 - REFERENCE JEDEC REGISTRATION MS-004, VARIATION CB, DATED 7/90.

| | | | |
|--|-------------------------|---|------------------|
| MIL/AERO CONFIGURATION CONTROL | | NATIONAL SEMICONDUCTOR CORPORATION <small>2300 Semiconductor Drive, Santa Clara, Ca. 95052-8090</small> | |
| | | LEADLESS CHIP CARRIER, TYPE C, 20 TERMINAL | |
| APPROVALS <small>DRN: Deane Gedy</small> <small>DWG. CHK.</small> <small>ENGR. CHK.</small> <small>APPROVAL</small> | DATE 02/10/94 | SCALE N/A | SIZE C |
| | | DRAWING NUMBER MKT-E20A | REV E |
| DO NOT SCALE DRAWING | | | SHEET 1 of 1 |

REV I S I O N S

| LTR | DESCRIPTION | E.C.N. | DATE | BY/APP'D |
|-----|--------------------------------|--------|----------|----------|
| L | REVISE PER CURRENT STD; REDRAW | 10002 | 09/21/93 | TL/ |



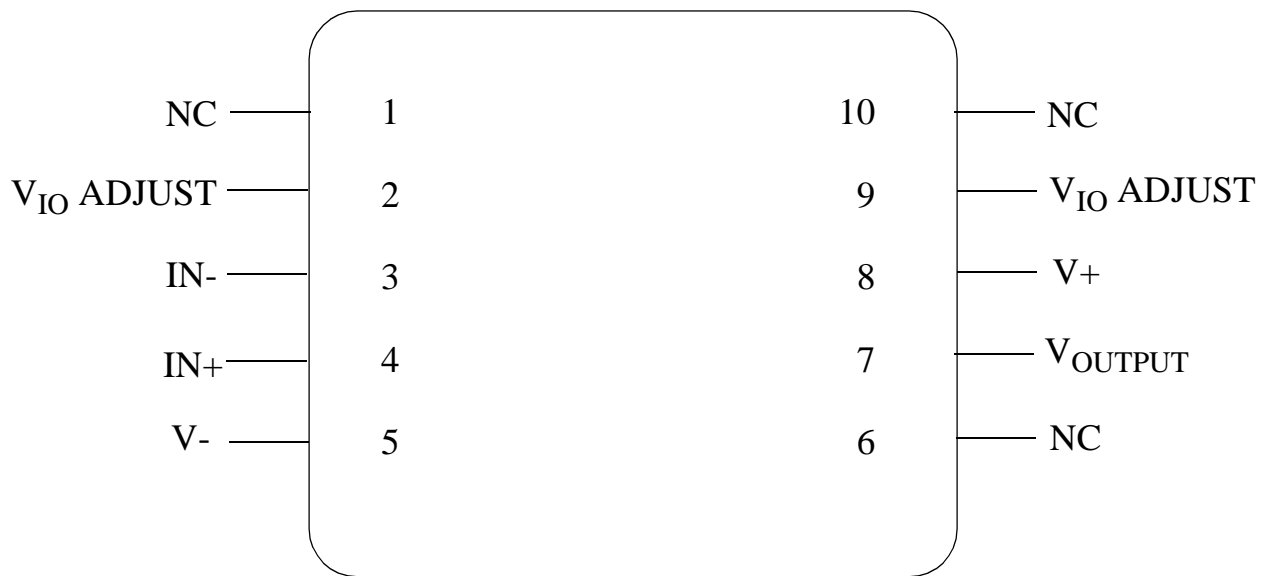
MILAERO
CONFIGURATION CONTROL
MIL-M-38510
CONFIGURATION CONTROL

CONTROLLING DIMENSION: INCH

| APPROVALS | DATE | NATIONAL SEMICONDUCTOR CORPORATION 2900 Semiconductor Drive, Santa Clara, CA 95052-8090 | |
|-------------------------|----------|--|----------------|
| DRAWN <i>T. LEQUANG</i> | 09/21/93 | SCALE | DRAWING NUMBER |
| DFTG. CHK. | | N/A | B |
| ENGR. CHK. | | DO NOT SCALE DRAWING | SHEET |
| APPROVAL | | | 1 OF 1 |
| INCH [MM] | | SIZE | REV |
| | | MKT-J08A | L |
| | | CERDIP (J), 8 LEAD | |

NOTES: UNLESS OTHERWISE SPECIFIED

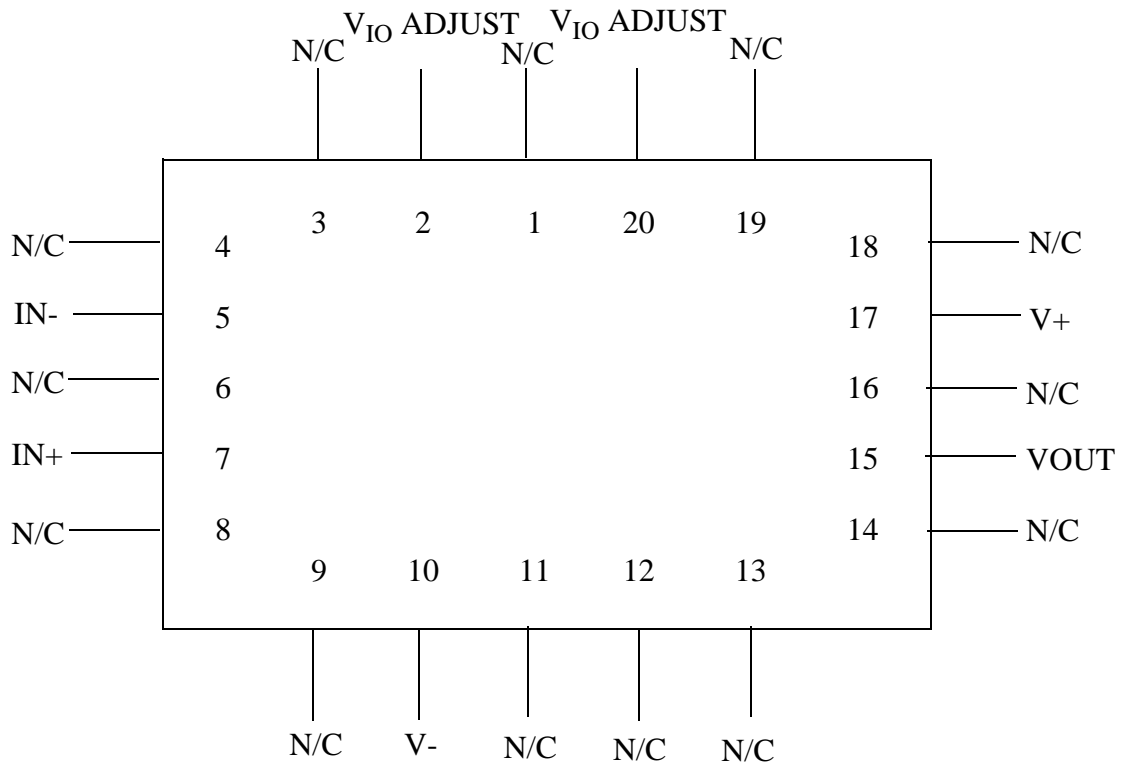
- LEAD FINISH TO BE 200 MICROMETERS / 5.08 MICROMETERS MINIMUM SOLDER MEASURED AT THE CREST OF THE MAJOR FLATS.
- JEDEC REGISTRATION MO-036, VARIATION AA, DATED 04/1981.



LM6161W
10 - LEAD CERPACK
CONNECTION DIAGRAM
TOP VIEW
P000167A



National Semiconductor™
MIL/AEROSPACE OPERATIONS
2900 SEMICONDUCTOR DRIVE
SANTA CLARA, CA 95050



LM6161E
20 - LEAD LCC
CONNECTION DIAGRAM
TOP VIEW
P000168B



National Semiconductor™

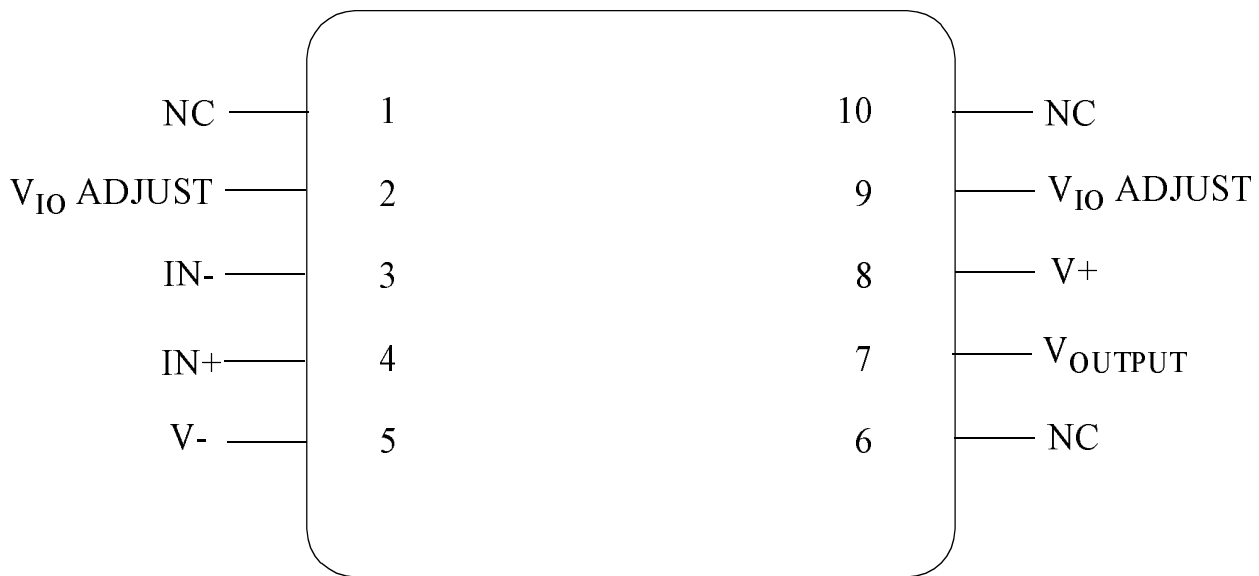
MIL/AEROSPACE OPERATIONS
 2900 SEMICONDUCTOR DRIVE
 SANTA CLARA, CA 95050



LM6161J
8 - LEAD DIP
CONNECTION DIAGRAM
TOP VIEW
P000169A



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2900 SEMICONDUCTOR DRIVE
SANTA CLARA, CA 95050

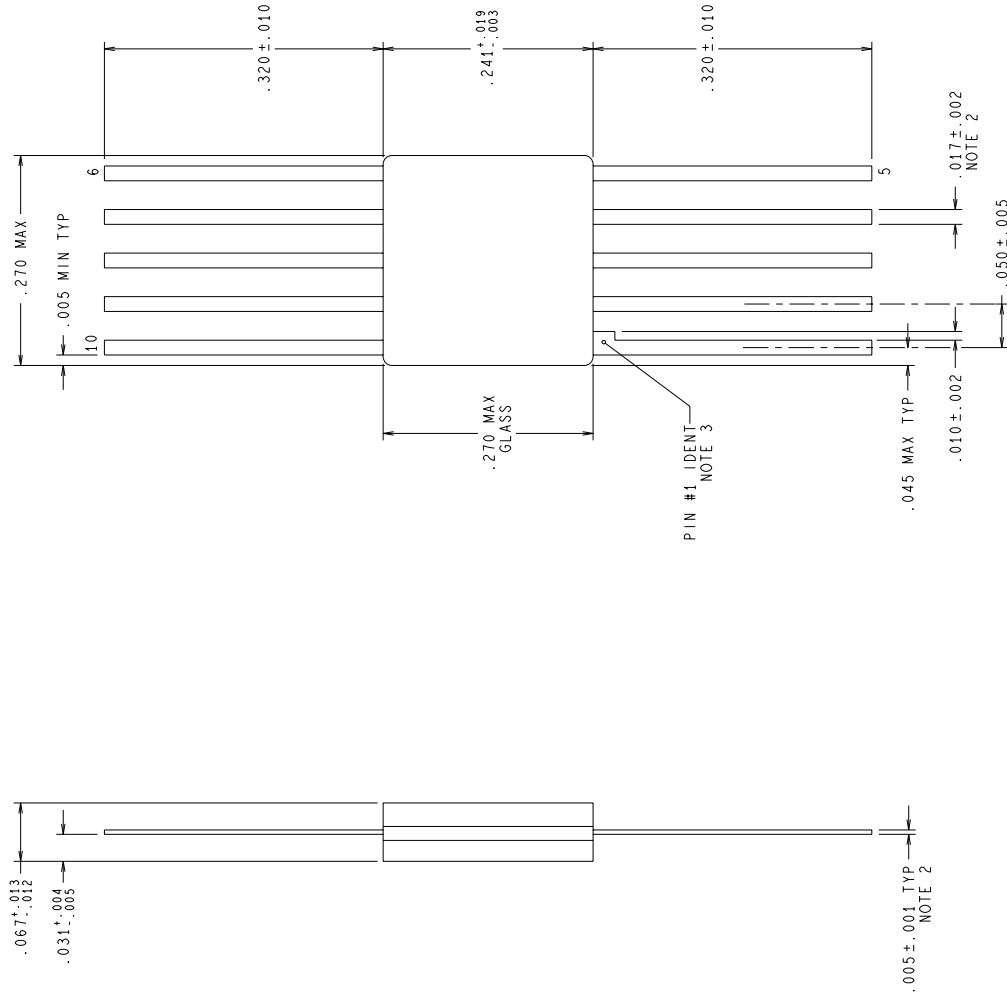


LM6161WG
10 - LEAD CERAMIC SOIC
CONNECTION DIAGRAM
TOP VIEW
P000259A



National Semiconductor™
MIL/AEROSPACE OPERATIONS
2900 SEMICONDUCTOR DRIVE
SANTA CLARA, CA 95050

| REVISIONS | | | |
|-----------|-------------------------------------|--------|------------------|
| LTR | DESCRIPTION | E.C.N. | DATE |
| F | REVISE AND REDRAW PER NEW STANDARD. | 10510 | 07/28/94 DEG/AEP |
| G | .017±.002 WAS .017±.020. | 10654 | 10/21/94 DEG/ |



NOTES: UNLESS OTHERWISE SPECIFIED.

- LEAD FINISH: SOLDER DIPPED WITH Sn60 OR Sn63 SOLDER CONFORMING TO MIL-M-38510 TO A MINIMUM THICKNESS OF 200 MICRONS. SOLDER MAY BE APPLIED OVER LEAD BASIS METAL OR Sn PLATE.
- MAXIMUM LIMIT MAY BE INCREASED BY .003 INCHES AFTER LEAD FINISH APPLIED.
- LEAD 1 IDENTIFICATION SHALL BE:
 - A NOTCH OR OTHER MARK WITHIN THIS AREA
 - A TAB ON LEAD 1, EITHER SIDE
- REFERENCE JEDEC REGISTRATION M0-003, VARIATION AG, DATED 06/01/76.

MIL/AERO
CONFIGURATION CONTROL

MIL-M-38510
CONFIGURATION CONTROL

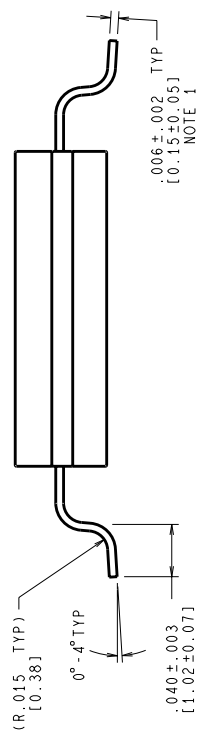
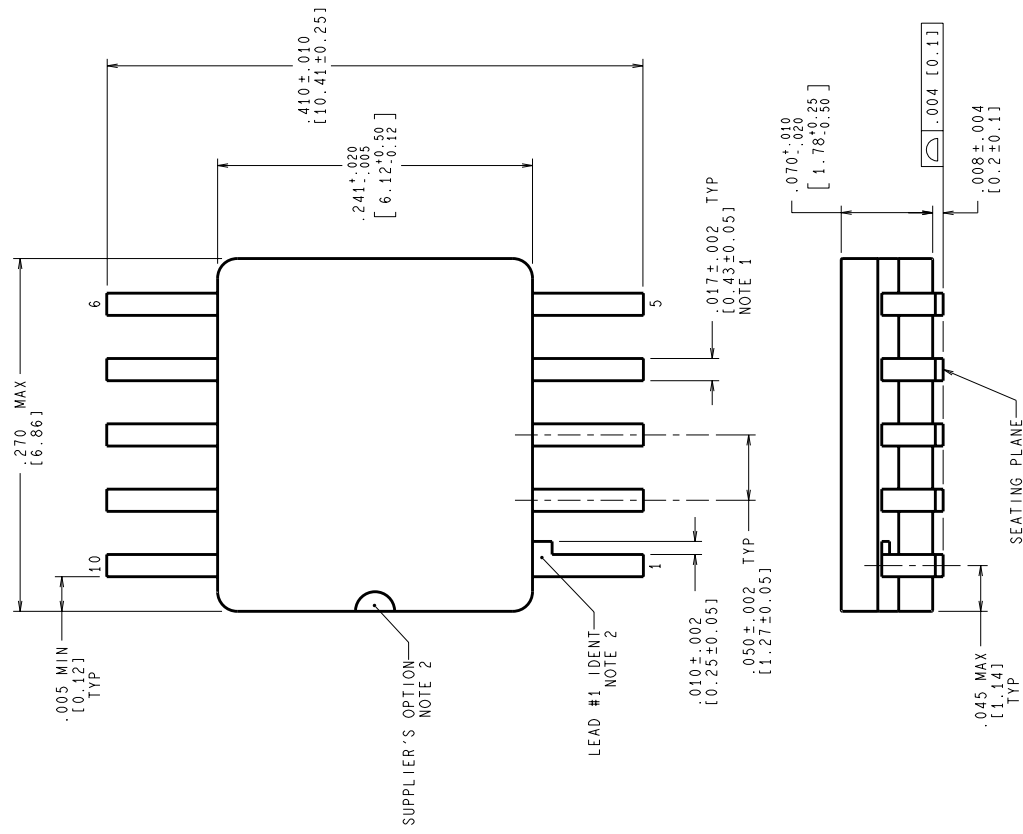
| APPROVALS | | DATE | |
|------------|--------------------|------|----------|
| DRWN | <i>D. F. Grady</i> | | 07/28/94 |
| DTG. CHK. | | | |
| ENGR. CHK. | | | |

| | | | |
|--|---|----------------|-------|
|  National Semiconductor 2800 Semiconductor dr., Santa Clara, CA 95052-8090 | | | |
| SCALE | | DRAWING NUMBER | |
| N/A | C | MKT-W10A | REV G |
| DO NOT SCALE DRAWING | | | |

CERPACK, 10 LEAD

REVISIONS

| LTR | DESCRIPTION | E.C.N. | DATE | BY/APP'D |
|-----|---|--------|------------|----------|
| A | RELEASE TO DOCUMENT CONTROL | 11374 | 02/29/1996 | MS/KH |
| B | LD PITCH TOL WAS ±.005; CHANGE LD RADIUS TO REF DIM; REMOVE THE OTHER R.006±.002 DIM. .040±.003 WAS .037±.003 | 11441 | 04/19/1996 | MS/KH |
| C | R .015(0.38) WAS R .006(0.15) | 11838 | 10/08/1997 | TL/ |



CONTROLLING DIMENSION IS INCH
VALUES IN | ARE MILLIMETERS

MIL-PRF-38535
CONFIGURATION CONTROL

NOTES: UNLESS OTHERWISE SPECIFIED

- LEAD FINISH: SOLDER DIPPED WITH Sn60 OR Sn63 SOLDER CONFORMING TO MIL-PRF-38535 TO A MINIMUM THICKNESS OF 200 MICRONS/ 5.08 MICROMETERS. SOLDER MAY BE APPLIED OVER LEAD BASIS METAL OR Sn PLATE. MAXIMUM LIMIT MAY BE INCREASED BY .003 IN/ 0.08mm AFTER LEAD FINISH APPLIED.
- LEAD IDENTIFICATION SHALL BE:
 - A NOTCH OR OTHER MARK WITHIN THIS AREA
 - A TAB ON LEAD 1, EITHER SIDE
- NO JEDEC REGISTRATION AS OF FEBRUARY 1996.

| APPROVALS | DATE | SCALE | SIZE | DRAWING NUMBER | REV |
|----------------------|----------|-------|------|----------------|-----|
| DRN: MARYA SUCHY | 02/29/96 | N/A | C | (SC)MKT-WG10A | C |
| DATE CHK: | | | | | |
| ENGR. CHK: | | | | | |
| PROJECTION | | | | | |
| | | | | | |
| DO NOT SCALE DRAWING | | | | | |
| SHEET 1 of 1 | | | | | |

National Semiconductor
2800 Semiconductor Dr., Santa Clara, CA 95052-8090

**CERPACK,
10 LEAD,
GULL WING**

Revision History

| Rev | ECN # | Rel Date | Originator | Changes |
|-----|----------|----------|---------------|--|
| 1A1 | M0002843 | 11/23/98 | Barbara Lopez | Update MDS: MNL6161-X Rev. 0B0 to MNL6161-X Rev. 1A1. Updated NSID, deleted W-SMD and added WG ID. Added SMD number for WG package. Added WG package to thermal resistance, updated note 6, deleted note 7, added power dissipation limit in Absolute section. Updated Subgroups to match SMD, added note 2 to Electrical section. Added MKT graphic for WG package. Added Pinouts for all packages. Added Burn-In CKT for W and E packages. |
| 2A1 | M0003073 | 09/04/02 | Rose Malone | Update MDS: MNL6161-X, Rev. 1A1 to MNL6161-X, Rev. 2A1. |
| 2B1 | M0004061 | 09/04/02 | Rose Malone | Update MDS: MNL6161-X, Rev. 2A1 to MNL6161-X, Rev. 2B1. Deleted reference to NSID LM6161W-SMD from Main Table. NSID no longer on CPL/SWIS. |